

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Brian S. Beaman et al.

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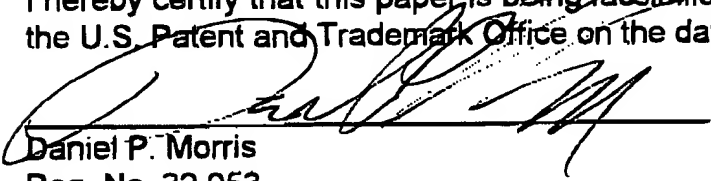
Filed: November 20, 1996

Examiner: V. Nguyen

For: A HIGH DENSITY INTEGRAL TEST PROBE AND FABRICATION METHOD

The Commissioner of Patents and Trademarks
Washington, D.C. 20231

I hereby certify that this paper is being facsimile transmitted under Rule CFR 1.61(d) to the U.S. Patent and Trademark Office on the date shown above.


Daniel P. Morris
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AMENDMENT

Sir:

In response to the Office Action dated August 3, 1998, please consider the following:

IN THE CLAIMS

In claim 16, line 6 before " ; " add

in a substantially perpendicular direction with respect to said surface.

In claims 16 and 49, last line before " . " add

said elongated electrical conductors remain in said substantially perpendicular

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